ISO 19463:2018 (E)

Microbeam analysis — Electron probe microanalyser (EPMA) — Guidelines for performing quality assurance procedures

Contents

Foreword

Introduction

1 Scope

2 Normative references

3 Terms and definitions

4 General principles of electron probe microanalyser quality assurance (EPMA QA)

- 4.1 Objective
- 4.2 Selection of challenge materials
- 4.2.1 General
- 4.2.2 General characteristics of analysed materials
- 4.2.3 Specific characteristics of challenge materials
- 4.3 QA measurement parameters
- 4.3.1 General
- 4.3.2 Laboratory environment preparation
- 4.3.3 Instrument parameters
- 4.3.3.1 General
- 4.3.3.2 Accelerating voltage
- 4.3.3.3 Probe current
- 4.3.3.4 Spectrometer and diffracting crystal selection
- 4.3.3.5 Peak and background energy selection
- 4.3.3.6 Selecting the analysis positions on the challenge material and the reference material
- 4.3.3.7 Selecting the optimum X-ray counting times
- 4.3.3.7.1 General
- 4.3.3.7.2 Peak counting time
- 4.3.3.7.3 Background counting time
- 4.4 Data acquisition
- 4.5 Frequency of QA diagnostic testing

5 Test report

6 Data analysis and performance tracking

- 6.1 General
- 6.2 Quantitative analysis of the challenge material
- 6.3 Calculation of means and standard deviations
- 6.4 Statistical tests performed on data
- 6.4.1 General
- 6.4.2 Normality test
- 6.4.3 Variance test

Annex A (informative) Examples of challenge materials and reference materials for EPMA WDS QA

- A.1 Selected challenge materials and reference materials

Annex B (informative) Distinguishing specimen preparation effects from instrument malfunction

- B.1 Specimen preparation
- B.1.1 Correct specimen preparation for optimal EPMA analysis
- B.1.2 Elemental composition total is below 100 %
- B.1.2.1 General
- B.1.2.2 Deviation from unity at the instrument’s uncertainty specification

B.1.2.2.1 Rough specimen
B.1.2.2.2 Tilted specimen with respect to standard
B.1.2.2.3 Crystalline specimen
B.1.2.3 Deviation from unity above the instrument uncertainty specification
B.1.2.3.1 General
B.1.2.3.2 Subsurface voids
B.1.2.3.3 Porous specimen
B.1.2.3.4 Contaminated specimen
B.1.2.3.5 Edge effects
B.1.3 Total elemental composition is above 100 % (within manufacturer’s specification for reproducibility or uncertainty)
B.1.3.1 Rough specimen
B.1.3.2 Tilted specimen with respect to standard
B.1.4 Total elemental composition is 100 % (uncertainties are higher than instrumental uncertainty)
B.1.4.1 Compositionally heterogeneous specimens
B.1.4.2 Multi-phase specimens
B.1.4.3 Variations of composition within a single phase
B.1.5 Summary

Annex C (informative) Graphical rendering of data and control charting

C.1 Introduction
C.2 Electron beam current tracking
C.3 Control charting
C.3.1 General
C.3.2 Univariate and multivariate mean and standard deviation ($\overline{x}$ and R) plots
C.3.3 Quartile (“box-and-whisker”) plots
C.3.4 Density (“bean”) plots

Annex D (informative) Failure modes indicated by test results

D.1 Introduction
D.2 Electron emitter malfunction
D.2.1 General
D.2.2 Electrostatic discharge
D.2.3 Drift instability
D.2.4 Emission noise instability
D.3 Diffracting crystal failure
D.3.1 General
D.3.2 Fractured diffracting crystal
D.3.3 Contaminated diffracting crystal
D.4 Detector failure
D.4.1 General
D.4.2 Contaminated detector
D.4.2.1 General
D.4.2.2 Detector window or surface contamination
D.4.2.3 Internal contamination
D.4.3 Charging detector window
D.5 X-ray energy analyser (Rowland circle) motion failure
D.5.1 General
D.5.2 Failure to drive correctly to a peak or background energy
D.5.3 Failure of backlash compensation at a peak energy
D.6 Alignment failures
D.6.1 General
D.6.2 Electron beam alignment
D.6.3 Spectrometer alignment
D.6.4 Diffracting crystal alignment
D.7 Diffracting crystal exchange failure

Page count: 30